Continuous Monitoring of Vanadium Oxytrichloride Impurities during the Manufacture of TiO₂

Vanadium oxytrichloride (VOCl₂) is

a common impurity that is difficult

to remove. Because the quality of

the TiCl, produced directly affects

the quality of the TiO, pigment

and titanium metal, it is important

Finally, the TiCl, is oxidized to

to monitor TiCl, purity.

 $\text{TiCl}_4 + \text{O}_2 \rightarrow \text{TiO}_{2 \text{ (pure)}} + 2\text{Cl}_2$

The AMETEK IPS-4 Diode

Array Spectrophotometer, a full

spectrum analyzer, is well suited

for this measurement. After

collecting the spectrum the

on-board computer performs

a full spectrum analysis in the

determination of VOCI, in TiCI,

produce pure TiO,

Titanium tetrachloride (TiCl,) is an intermediate in the production of titanium dioxide (TiO₂) as well as titanium metals and alloys. TiO, is a white pigment used primarily in the paint, plastic and paper industries for its superior ability to completely mask a substrate

Measurement Requirement

TiCl, purity is monitored in the manufacture of TiO₂. The presence of vanadium, in the form of vanadium oxytrichloride, VOCI, in TiCl, is an impurity that affects the quality of the TiO₂. The AMETEK IPS-4 Diode Array Spectrophotometer can be used to monitor VOCI, in TiCl, production, with typical ranges either in 0-20 ppmW or 0-40 ppmW VoCl, in TiCl,

Process Overview

TiO, is primarily manufactured using the chloride process, during which rutile (mostly TiO₂) is converted to TiCl, by reacting the ore with Cl, gas around 900°C.

$$[\text{TiO}_2]_{\text{ore}} + 2\text{Cl}_2 + \text{C} \rightarrow \text{TiCl}_{4(v)} + \text{CO}_2$$

Next, other trace metal chlorides are removed using fractional distillation to refine the TiCl₄.



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The total time measurement and calculations is less than 4 seconds. The multivariate calibration accounts for specific interferences caused by the sample stream. The IPS-4 is capable of monitoring specific wavelengths and performing multi-component analysis. For this application, measurements are taken between 365 and 450 nm to avoid inherent interferences of the process.

The IPS-4's unique flow cell design separates the process sample from the spectrophotometer, simplifying installation and eliminating any possibility of sample damage to the electronics.



AMETEK's IPS-4 Diode Array Spectrophometer





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